

FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 00-VE04.75ACIP		SERIAL NO. 09/767,902	
LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT(S): Doskow et al.			
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							YES NO
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EXAMINER	/Quynh Nguyen/				DATE CONSIDERED 10/11/2006		
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